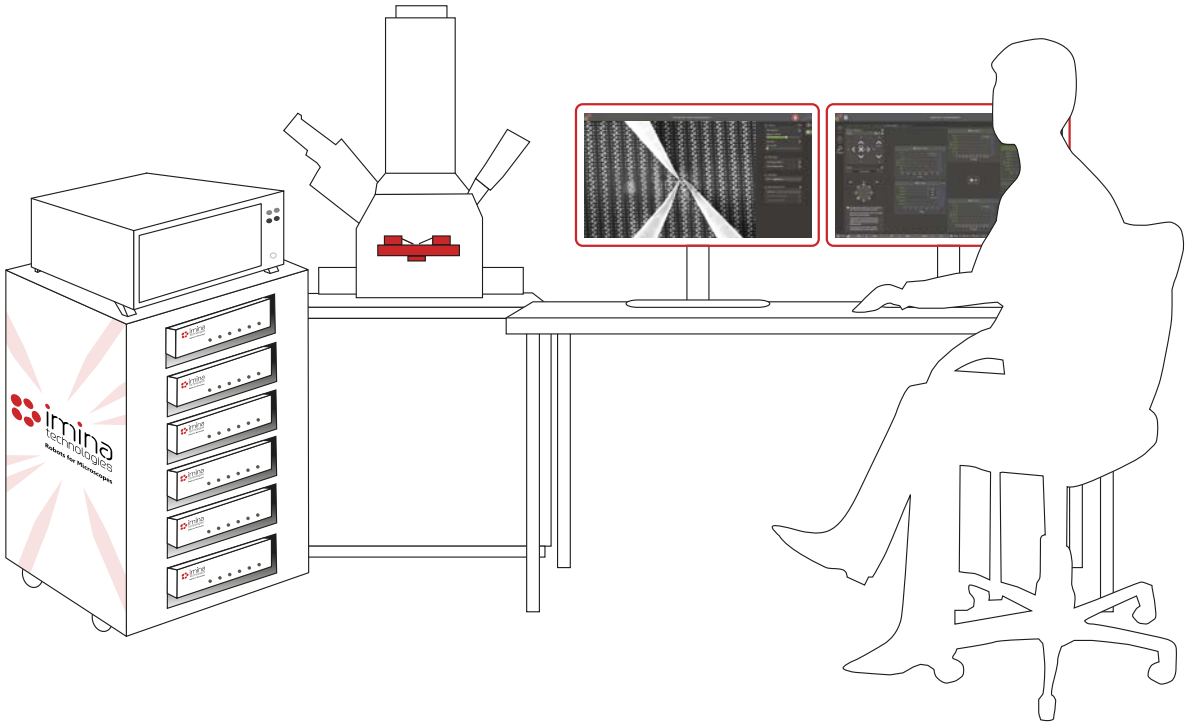
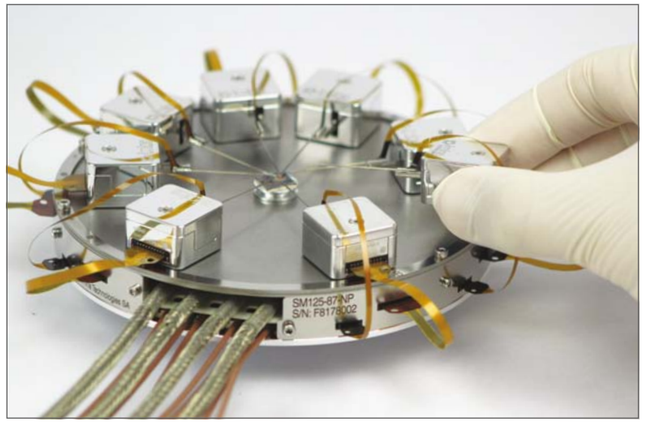
Robots for Microscopes.

imina technologies

Nanoprobing SEM Solutions



Position probe tips in contact with semiconductor chips, measure the electrical characteristics of integrated components and isolate defects.



Easily reposition probers around samples with variable sizes and geometries and quickly change probe tips.

Imina Technologies' Nanoprobing SEM Solutions are turnkey for electrical characterization of microelectronic devices and in situ semiconductor failure analysis.

Up to 8 nanoprobers can be delivered in various configurations to adapt to customer applications requirements and equipment.

The circular platforms can either be mounted on the SEM sample positioning stage, or be loaded via the SEM load-lock.

Best in class in situ preamplifiers and scan generators are compatible with the Nanoprobing Solutions to perform quantitative EBIC and low noise EBAC/RCI analyses.

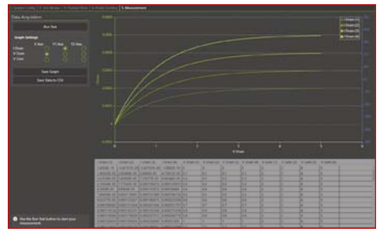
The **Nanoprobing module** of **Precisio™** software suite is a step by step workflow that provides assistance to the operator from setting up the system, to landing probe tips on the device under test and acquiring measurement data. Utility functions as tip to tip contact testing and in situ tips cleaning are also available.

Test Recipes.

Create new or load existing measurement projects. Select the type of device under test (transistor, diode, resistor, etc.) from a library and remotely configure the Keithley 4200-SCS to match your characterization needs.

Tip Contact Detection.

Get a visual feedback with I-V traces to optimize each probe tip contact resistance with the substrate. Individually configure the contact tests to cycle according to the specifications of the device under test. Run automatic test sequences over all probes.

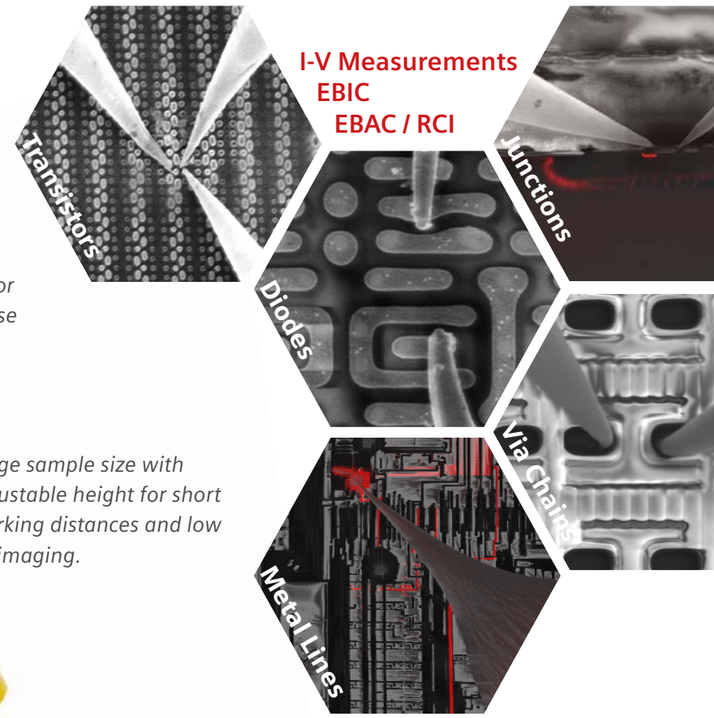


Measurements & Reporting.

Run series of pre-configured tests. Display results on graphs to ease comparison. Store raw and graph data for post-processing and reporting.

Benefits

- Up to 8 independent nanometer positioning resolution probers to achieve steady electrical contacts on even the smallest chip technologies.
- Installation of in situ equipment achieved in minutes without permanent modifications of the SEM, avoiding the need for a dedicated microscope.
- Comprehensive nanoprobing workflow fully managed from Precisio™, a unified and intuitive software suite to control the nanoprobers and acquire measurements.
- Swiss quality product engineering and manufacturing with long term warranties.
- Tailored service contracts with recognized customer support for product installation, maintenance and staff training.

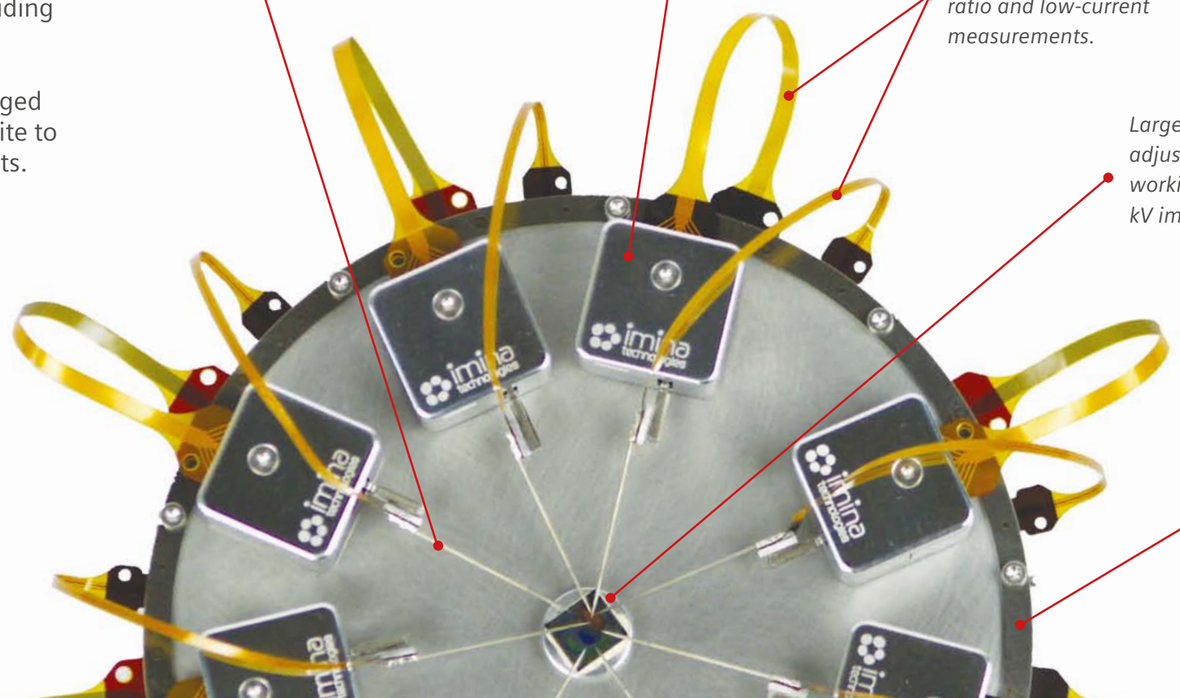


Tungsten probe needles with tip radii down to 5 nm.

Micro-robots with unique mobile motion technology for intuitive positioning control.

Independent cabling for excellent signal-to-noise ratio and low-current measurements.

Large sample size with adjustable height for short working distances and low kV imaging.



Light and compact platforms compatible with even the smallest SEM vacuum chambers.

Ø100 mm (4-Bot)
Ø125 mm (8-Bot)

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